Se	earch Notes	•

Application/Control No.	Applicant(s)/Patent under Reexamination
10/622,413	MEIJER ET AL.
Examiner	Art Unit
Kou-Yi K. Chen	2193

SEARCHED				
Class	Subclass	Date	Examiner	
717	114-118	3/6/2006	K.C.	
. 717	136-140	3/6/2006	K.C.	
717	.146-147	3/6/2006	K.C.	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
-	DATE	EXMR
US-PGPUB; USPAT; USOCR; EPO; JPO, DERWENT; IBM_TDB (limited classified search)	3/6/2006	K.C.
Inventor name search	3/3/2006	K.C.
IEEE/ACM search	3/3/2006	K.C.
Google search	3/3/2006	K.C.
Consulted with SPE regarding 101 issue	3/6/2006	K.C.